

Form PTO-1449

U.S. DEPARTMENT OF COMMERCE  
PATENT AND TRADEMARK OFFICEATTY. DOCKET NO.  
M122-1943SERIAL NO.  
10/071,456LIST OF ART CITED BY APPLICANT  
(Use several sheets if necessary)APPLICANT  
David L. Dickerson et al.FILING DATE  
February 8, 2002GROUP  
2814

## U.S. PATENT DOCUMENTS

*Examining Division		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
A.M.	AA	5,399,520	03/21/95	Jang			
	AB						
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		Document Number	Date	Country	Class	Subclass	Translation	
							Yes	No
	AM							
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AM	AR	K. Ishimaru et al., <i>Trench Isolation Technology with 1 Micron Depth n-and p-Wells for a Full CMOS SRAM Cell with a 0.4 Micron . . .</i> IEEE 1994 pgs. 97-98
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